What is claimed is:

[Claim 1]

A polycrystalline silicon rod, wherein an outer layer part which is 4 mm deep from a surface has a Fe concentration of 10.0 pptw or less, or a Ni concentration of 2.0 pptw or less and a foreign object having a size of 0.5 to 10 cm and a height of 0.5 to 5.0 cm is two or less per 100000 cm^2 surface area of the polycrystalline silicon rod.

[Claim 2]

The polycrystalline silicon rod according to claim 1, wherein a volume average of a Fe concentration is 20 pptw or less, or a Ni concentration is 2.0 pptw or less which are calculated from actual measured values in a core wire part, a middle part, and the outer layer part.